Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
09/601,591	MERIC ET AL.
Examiner	Art Unit
Michael W. Hoye	2623

SEARCHED				
Class	Subclass	Date	Examiner	
725	31, 131- 132, 139, 140, 151- 152	9/21/2004	JM	
380	28, 255	9/29/2004	JM	
380	240-242	9/29/2004	JM	
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Updated	Search	11/4/2005	JM	
Updated	Search	5/24/2006	JM	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Consulted: Chris Nalevanko - Class 725 IEEE Search	9/27/2004	JM
Consulted: Chris Grant - Class 725	9/29/2004	JM
EAST Search	9/30/2004	JM
EAST Search	11/4/2005	JM
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